

P603-1 / P750 set

基于IEC61967-4标准的传导发射测量



Short description

该探头套组用于测量IC引脚的传导发射（采用1欧姆/150欧姆直接耦合进行测量）。它基于IEC61967-4标准，分别有一个用于测试电流和电压的探头。该探头能够接触到测试IC的每个引脚。

该探头套组能够确保较高的测量重复精度和测量的可比较性。

使用朗格尔电磁兼容技术公司的ICE1集成电路IC测试环境，可以对待测集成电路进行测试。芯片扫描ChipScan-ESA 软件系统可以控制测量过程，并对所有引脚的测量数据进行存储以及快速系统地分析比较。

The measurements with the probe set guarantee a high precision when repeated and comparability of measurements.

The ICE1 IC test environment of Langer EMV-Technik is used to start the test IC. measurements can be done with ChipScan-ESA software. Measurement results of all measured pins are saved in the software and can be compared fast and systematically.

Delivery content

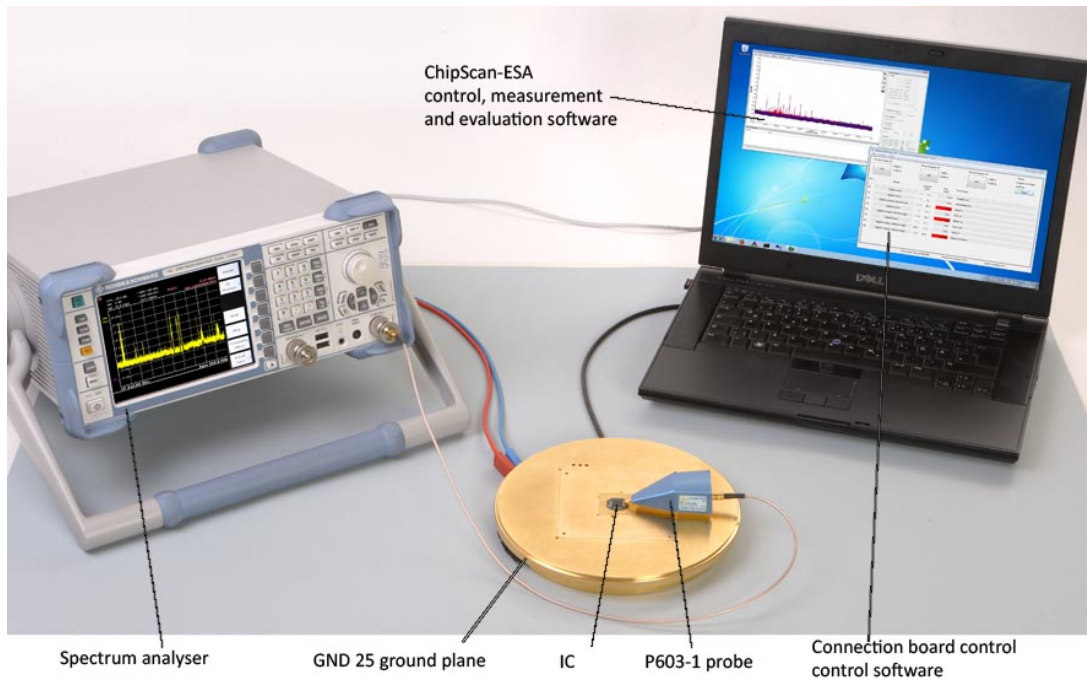
- 1x P603-1, 1 Ω 高频电流表 SMA
- 1x P750, 150 Ω 高频电压表
- 1x CS-ESA, ESA芯片扫描软件
- 1x SMA-SMB 1 m, SMA-SMB 测量电缆
- 1x NT FRI EU
- 1x P603 / P750 case, System case
- 1x P603-1 / P750 m, SMA

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Application with P603-1



Scheme measurement set-up with P750

